

# **OptiMOS**<sup>™</sup>3 Power-Transistor

#### **Features**

- Ideal for high frequency switching and DC/DC converters
- Excellent gate charge x R DS(on) product (FOM)
- Very low on-resistance R<sub>DS(on)</sub>
- N-channel, normal level
- 100% avalanche tested
- Pb-free plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Halogen-free according to IEC61249-2-21

Туре	IPB036N12N3 G
	1 tab
Package	PG-TO263-7
Marking	036N12N

## **Product Summary**

V <sub>DS</sub>	120	٧
$R_{\mathrm{DS(on),max}}$	3.6	mΩ
I <sub>D</sub>	180	Α







Maximum ratings	at T =25 °C	unless otherwis	a specified
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Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I <sub>D</sub>	T <sub>C</sub> =25 °C <sup>2)</sup>	180	А
		T <sub>C</sub> =100 °C	139	
Pulsed drain current <sup>2)</sup>	I <sub>D,pulse</sub>	T <sub>C</sub> =25 °C	720	
Avalanche energy, single pulse <sup>3)</sup>	E <sub>AS</sub>	$I_{\rm D}$ =100 A, $R_{\rm GS}$ =25 $\Omega$	900	mJ
Gate source voltage	$V_{GS}$		±20	V
Power dissipation	$P_{\text{tot}}$	T <sub>C</sub> =25 °C	300	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

 $<sup>^{1)}\</sup>text{J-STD20}$  and JESD22

 $<sup>^{2)}</sup>$  See figure 3 for more detailed information

<sup>&</sup>lt;sup>3)</sup> See figure 13 for more detailed information



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - case	$R_{\mathrm{thJC}}$		-	-	0.5	K/W
Thermal resistance,	$R_{\mathrm{thJA}}$	minimal footprint	-	-	62	
junction - ambient		6 cm <sup>2</sup> cooling area <sup>4)</sup>	-	-	40	

# **Electrical characteristics,** at $T_j$ =25 °C, unless otherwise specified

#### Static characteristics

Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>(BR)DSS</sub> V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA		-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =270 μA	2	3	4	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C		0.1	1	μA
		V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	-	10	100	
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	-	1	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V <sub>GS</sub> =10 V, I <sub>D</sub> =100 A	1	2.9	3.6	mΩ
Gate resistance	R <sub>G</sub>		1	1.4	-	Ω
Transconductance	$g_{fs}$	V <sub>DS</sub>  >2 I <sub>D</sub>  R <sub>DS(on)max</sub> , I <sub>D</sub> =100 A	98	195	-	s

 $<sup>^{4)}</sup>$  Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm $^2$  (one layer, 70  $\mu$ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	10400	13800	pF
Output capacitance	Coss	V <sub>GS</sub> =0 V, V <sub>DS</sub> =60 V, f=1 MHz	-	1320	1760	
Reverse transfer capacitance	Crss		-	61	-	1
Turn-on delay time	$t_{d(on)}$		-	35	-	ns
Rise time	t <sub>r</sub>	V <sub>DD</sub> =60 V, V <sub>GS</sub> =10 V,	-	52	-	1
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =100 A, $R_{\rm G}$ =1.6 Ω	-	76	-	
Fall time	$t_{\mathrm{f}}$	]	-	21	-	
Gate Charge Characteristics <sup>5)</sup>	<u></u>	<u> </u>				Inc
Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =60 V, I <sub>D</sub> =100 A, V <sub>GS</sub> =0 to 10 V	-	52	-	nC
Gate to drain charge	Q <sub>gd</sub>		-	37	-	
Switching charge	$Q_{sw}$		•	57	-	
Gate charge total	Qg		ı	158	211	
Gate plateau voltage	V <sub>plateau</sub>		-	5.0	-	V
Output charge	Q <sub>oss</sub>	V <sub>DD</sub> =60 V, V <sub>GS</sub> =0 V	-	182	242	nC
Reverse Diode						
Diode continous forward current	Is	T -05 °O	-	-	180	Α
Diode pulse current	I <sub>S,pulse</sub>	- T <sub>C</sub> =25 °C	-	-	720	]
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0 V, I <sub>F</sub> =100 A, T <sub>j</sub> =25 °C	-	0.9	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =37.5 V, I <sub>F</sub> =I <sub>S</sub> ,	-	123	-	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100 A/µs	_	356	_	nC

 $<sup>^{5)}\,\</sup>mathrm{See}$  figure 16 for gate charge parameter definition



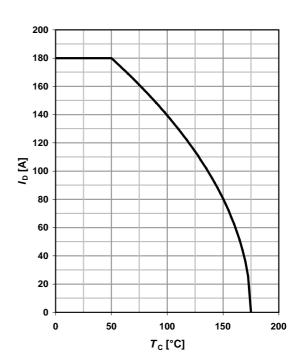
#### 1 Power dissipation

## $P_{\text{tot}}$ =f( $T_{\text{C}}$ )

# 

#### 2 Drain current

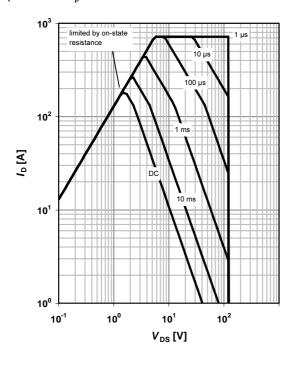
$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$



## 3 Safe operating area

$$I_D$$
=f( $V_{DS}$ );  $T_C$ =25 °C;  $D$ =0

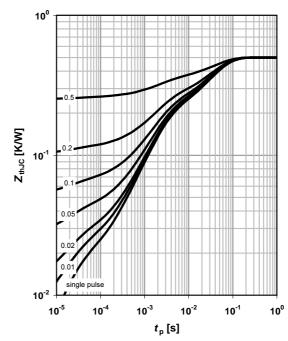
parameter:  $t_p$ 



## 4 Max. transient thermal impedance

$$Z_{\rm thJC}$$
=f( $t_{\rm p}$ )

parameter:  $D=t_p/T$ 

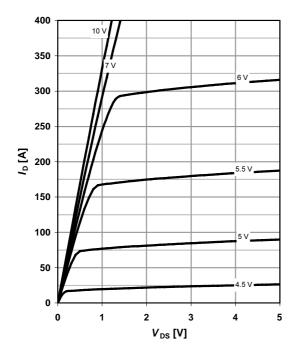




#### 5 Typ. output characteristics

 $I_D$ =f( $V_{DS}$ );  $T_j$ =25 °C

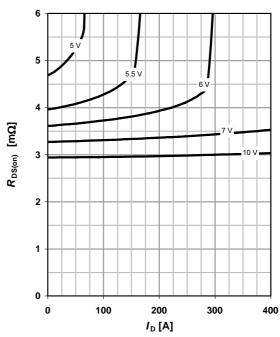
parameter: V<sub>GS</sub>



#### 6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f( $I_D$ );  $T_j$ =25 °C

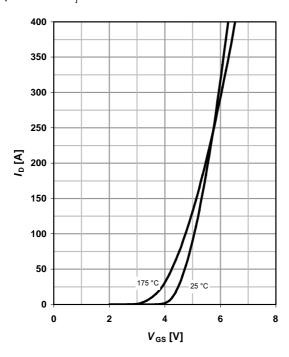
parameter: V<sub>GS</sub>



## 7 Typ. transfer characteristics

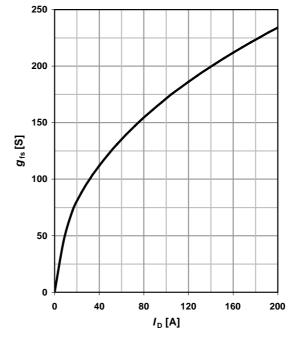
 $I_{D}$ =f( $V_{GS}$ );  $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$ 

parameter:  $T_j$ 



## 8 Typ. forward transconductance

$$g_{fs}$$
=f( $I_D$ );  $T_j$ =25 °C





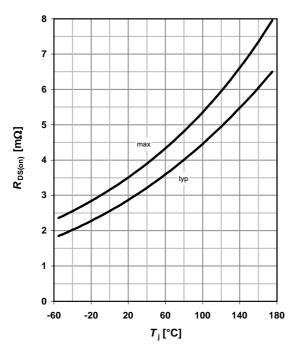
#### 9 Drain-source on-state resistance

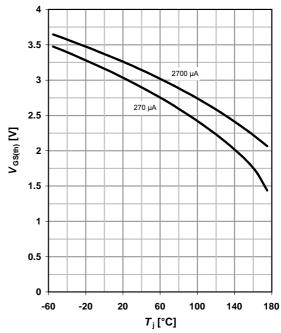
 $R_{DS(on)}$ =f( $T_j$ );  $I_D$ =100 A;  $V_{GS}$ =10 V

## 10 Typ. gate threshold voltage

 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$ 

parameter: I<sub>D</sub>





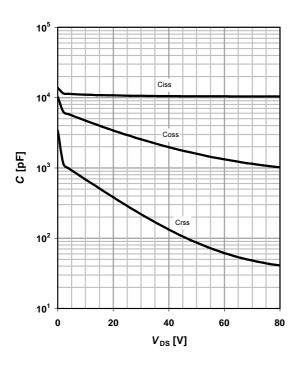
## 11 Typ. capacitances

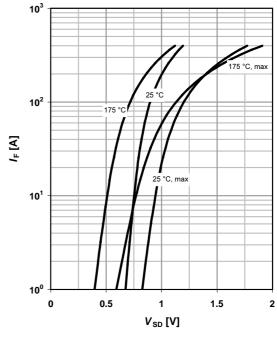
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$ 

### 12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$ 

parameter:  $T_{\rm j}$ 



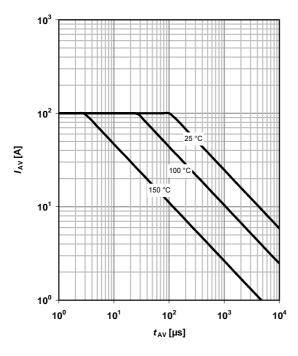




#### 13 Avalanche characteristics

 $I_{AS}$ =f( $t_{AV}$ );  $R_{GS}$ =25  $\Omega$ 

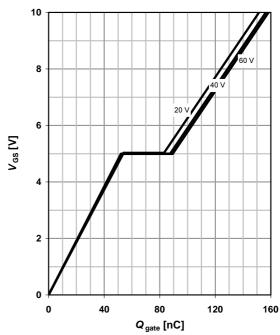
parameter:  $T_{\rm j(start)}$ 



## 14 Typ. gate charge

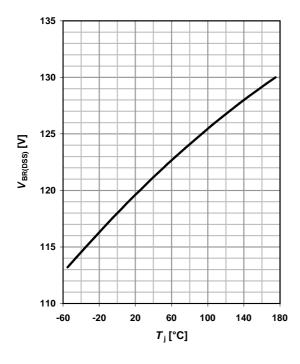
 $V_{\rm GS}$ =f(Q<sub>gate</sub>);  $I_{\rm D}$ =100 A pulsed

parameter:  $V_{\rm DD}$ 

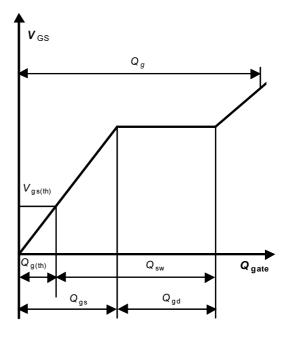


## 15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f( $T_j$ );  $I_D$ =1 mA

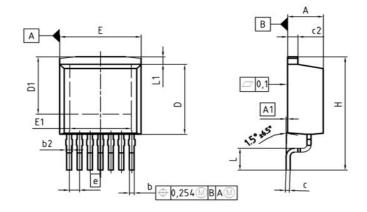


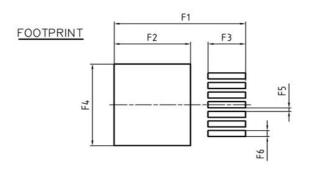
## 16 Gate charge waveforms





## PG-TO263-7





DIM	MILLIMETERS		INCH	HES	
DIM	MIN	MAX	MIN	MAX	
A	4.30	4.57	0.169	0.180	
A1	0.00	0.25	0.000	0.010	
Ь	0.50	0.70	0.020	0.028	
b2	0.50	1.00	0.020	0.039	
С	0.33	0.65	0.013	0.026	
c2	1.17	1.40	0.046	0.055	
D	8.51	9.45	0.335	0.372	
D1	6.90	7.90	0.272	0.311	
E	9.80	10.31	0.386	0.406	
E1	6.50	8.60	0.256	0.339	
е	1.27		0.050		
N		7		7	
Н	14.61	15.88	0.575	0.625	
L	2.29	3.00	0.090	0.118	
L1	0.70	1.60	0.028	0.063	
F1	16.05	16.25	0.632	0.640	
F2	9.30	9.50	0.366	0.374	
F3	4.50	4.70	0.177	0.185	
F4	10.70	10.90	0.421	0.429	
F5	0.37	0.57	0.015	0.022	
F6	0.70	0.90	0.028	0.035	

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